

**Search Notes**

Application/Control No.

10/757,399

Examiner

TUYEN T. NGUYEN

Applicant(s)/Patent under  
Reexamination

YEH ET AL.

Art Unit

2832

**SEARCHED**

Class	Subclass	Date	Examiner
336	65, 90-96, 107, 192, 198	3/31/2005	TTN
123	634-635	3/31/2005	TTN

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR